

FDS6612A

Single N-Channel, Logic Level, PowerTrench™ MOSFET

General Description

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

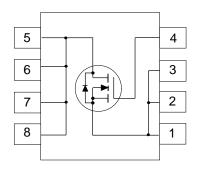
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

- 8.4 A, 30 V. $R_{DS(ON)} = 0.022 \ \Omega$ @ $V_{GS} = 10 \ V$, $R_{DS(ON)} = 0.030 \ \Omega$ @ $V_{GS} = 4.5 \ V$.
- Fast switching speed.
- Low gate charge.
- High performance trench technology for extremely low R_{DS(ON)}.
- High power and current handling capability.





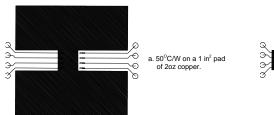


Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	FDS6612A	Units
V _{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	±20	V
D	Drain Current - Continuous (Note 1a)	8.4	A
	- Pulsed	40	
)	Power Dissipation for Single Operation (Note 1a)	2.5	W
	(Note 1b)	1.2	
	(Note 1c)	1	
Γ_{J} , T_{STG}	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	CHARACTERISTICS		·
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	50	°C/W
₹ _{⊌IC}	Thermal Resistance, Junction-to-Case (Note 1)	25	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25 °C		26		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \ V_{GS} = 0 \text{ V}$			1	μΑ
		$T_J = 55^{\circ}C$			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ON CHARAC	CTERISTICS (Note 2)			•	•	•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1	1.6	3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		-4.3		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 8.4 \text{ A}$		0.019	0.022	Ω
		T _J =125°C	;	0.027	0.037	
		$V_{GS} = 4.5 \text{ V}, I_D = 7.2 \text{ A}$		0.026	0.03	1
I _{D(ON)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \ V_{DS} = 5 \text{ V}$	20			Α
g _{FS}	Forward Transconductance	V _{DS} = 15 V, I _D = 8.4 A		19		S
DYNAMIC C	HARACTERISTICS		•	•	•	•
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \ V_{GS} = 0 \text{ V}, $ f = 1.0 MHz		830		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		185		pF
C _{rss}	Reverse Transfer Capacitance			80		pF
SWITCHING	CHARACTERISTICS (Note 2)					
t _{D(on)}	Turn - On Delay Time	$V_{DS} = 15 \text{ V}, I_{D} = 1 \text{ A}$		6	12	ns
t _r	Turn - On Rise Time	$V_{GS} = 10 \text{ V}$, $R_{GEN} = 6 \Omega$		10	18	ns
t _{D(off)}	Turn - Off Delay Time			18	29	ns
t,	Turn - Off Fall Time			5	12	ns
Q_g	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 8.4 \text{ A},$		9	13	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 5 V		2.8		nC
Q_{gd}	Gate-Drain Charge			3.1		nC
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAXIMU	JM RATINGS				
l _s	Maximum Continuous Drain-Source Diode Forward Current				2.1	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.1 \text{ A} \text{ (Note 2)}$		0.75	1.2	V

^{1.} R_{QUA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{QUC} is guaranteed by design while R_{QCA} is determined by the user's board design.







Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

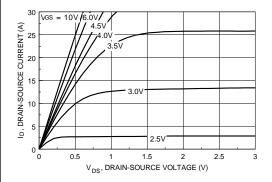


Figure 1. On-Region Characteristics.

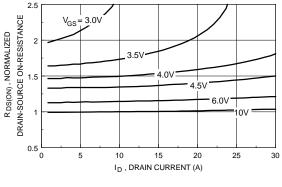


Figure 2. On-Resistance Variation with Dain Current and Gate Voltage.

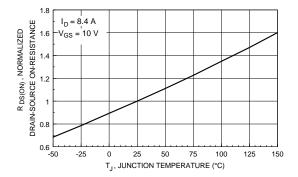


Figure 3. On-Resistance Variation with Temperature.

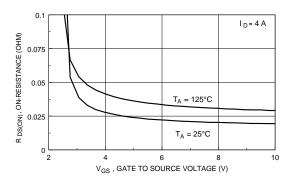


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

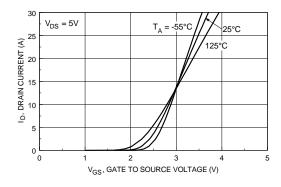


Figure 5. Transfer Characteristics.

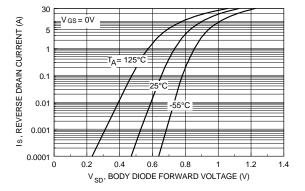


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical And Thermal Characteristics

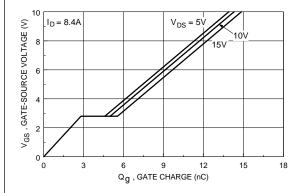


Figure 7. Gate Charge Characteristics.

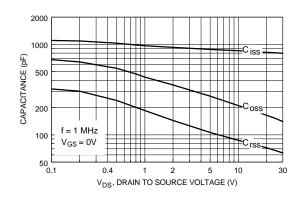


Figure 8. Capacitance Characteristics.

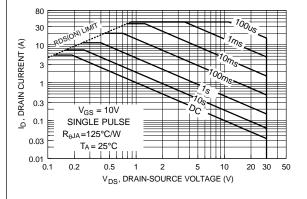


Figure 9. Maximum Safe Operating Area.

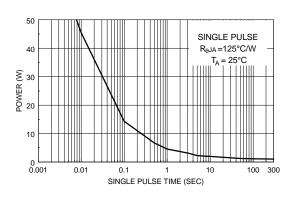


Figure 10. Single Pulse Maximum Power Dissipation.

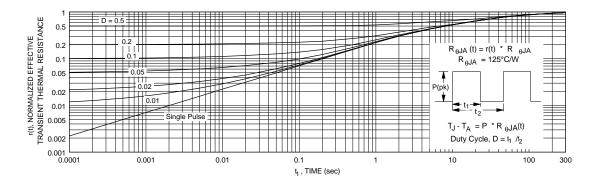


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.

Transient thermal response will change depending on the circuit board design.

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FACT™ QFET™ FACT Quiet Series™ QS™

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